

Notice of References Cited

Application No.

09/856,833

Applicant(s)

Goedicke et al

Examiner

T. Yoon

Group Art Unit

1714

Page 1 of 2

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*		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
✓	A	3,619,145	11/71	Crawford et al.		
✓	B	3,804,811	4/74	Rose et al		
✓	C	4,591,487	5/86	Fritsch		
✓	D	4,722,680	2/88	Rossberger et al		
✓	E	5,597,891	1/97	Nelson et al.		
✓	F	5,836,682	11/98	Blach		
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✓	N	915 689	7/54	Germany			
✓	O	1595735	8/69	"			
✓	P	0336 520	10/89	EP			
✓	Q	4001988	10/90	Germany			
✓	R	0560 033	9/93	EP			
✓	S	0588 008	3/94	EP			
✓	T	0788 867	8/97	EP			

NON-PATENT DOCUMENTS

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(See Manual of Patent Examining Procedure, Section 707.05(a).)

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			Examiner <i>T. Yoon</i>		Group Art Unit <i>1714</i>	
Pag <u>2</u> of <u>2</u>						
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✓ N	<i>0861717</i>	<i>9/98</i>	<i>EP</i>			
✓ O	<i>WO 98/40194</i>	<i>9/98</i>	<i>WO</i>			
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